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Standard Spectral Reflectance Measurements for ASD FieldSpec Spectroradiometer

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Pooja Vinod Janse ; Jaypalsing N. Kayte ; Rashmi V. Agrawal ; Ratnadeep R. Deshmukh All Authors



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Abstract:

Accurate and precise spectral measurements represent the objective material's properties. But some of the factors that are responsible for change in spectral signature which has effect on the quality of spectral measurement. These factors should be taken into consideration while taking measurement. These factors include environmental and experimental issues, the properties of the atmosphere, timing, orientation, and height of measurement, Field Of View (FOV), calibration of the spectral data and spectral averaging etc. This paper defines method for standard spectral reflectance measurements and the factors affecting the measurement.

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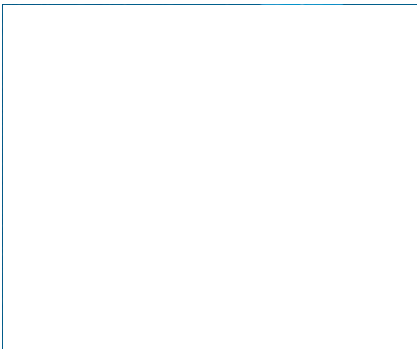
Contents



1 Introduction

Hyper spectral remote sensing provides facility to extract information from any material based on the spectra collected by ASD FieldSpec spectroradiometer [1]. This device provides us band information from 350nm to 2500nm, which covers visible region, Near Infrared region (NIR) and Shortwave Infrared region (SWIR) providing large set of information. Major challenges are faced by researchers while collecting spectral reflectance both on field and in controlled condition in laboratory.

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